

2A, 60V, 0.130 Ohm, Dual N-Channel, LittleFET™ Power MOSFET

This Dual N-Channel power MOSFET is manufactured using the latest manufacturing process technology. This process, which uses feature sizes approaching those of LSI integrated circuits, gives optimum utilization of silicon, resulting in outstanding performance. It is designed for use in applications such as switching regulators, switching converters, motor drivers, relay drivers, and low voltage bus switches. These devices can be operated directly from integrated circuits.

Formerly developmental type TA49154.

Ordering Information

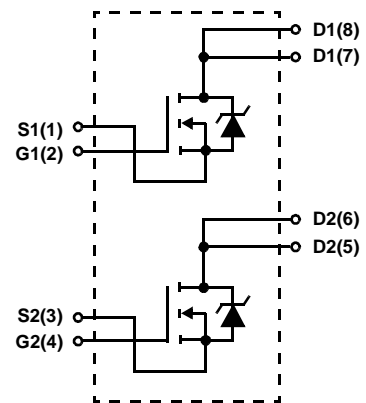
| PART NUMBER | PACKAGE | BRAND |
|-------------|----------|-----------|
| RF1K49154 | MS-012AA | RF1K49154 |

NOTE: When ordering, use the entire part number. For ordering in tape and reel, add the suffix 96 to the part number, i.e., RF1K4915496.

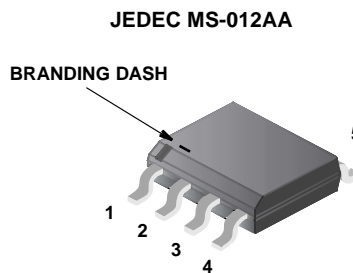
Features

- 2A, 60V
- $r_{DS(ON)} = 0.130\Omega$
- Temperature Compensating PSPICE® Model
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol



Packaging



RF1K49154

Absolute Maximum Ratings $T_A = 25^\circ\text{C}$, Unless Otherwise Specified

| | RF1K49154 | UNITS |
|---|-----------------------------|---------------------|
| Drain to Source Voltage (Note 1) | 60 | V |
| Drain to Gate Voltage ($R_{GS} = 20\text{k}\Omega$, Note 1) | 60 | V |
| Gate to Source Voltage | ± 20 | V |
| Drain Current Continuous (Pulse width = 5s) | 2 | A |
| Pulsed (Figure 5) | Refer to Peak Current Curve | |
| Pulsed Avalanche Rating (Figure 6) | Refer to UIS Curve | |
| Power Dissipation | 2 | W |
| Derate Above 25°C | 0.016 | W/ $^\circ\text{C}$ |
| Operating and Storage Temperature | -55 to 150 | $^\circ\text{C}$ |
| Maximum Temperature for Soldering | | |
| Leads at 0.063in (1.6mm) from Case for 10s | 300 | $^\circ\text{C}$ |
| Package Body for 10s, See Techbrief 334 | 260 | $^\circ\text{C}$ |

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^\circ\text{C}$ to 125°C .

Electrical Specifications $T_A = 25^\circ\text{C}$, Unless Otherwise Specified

| PARAMETER | SYMBOL | TEST CONDITIONS | MIN | TYP | MAX | UNITS |
|--|-----------------|---|-----|-----|----------|--------------------|
| Drain to Source Breakdown Voltage | BV_{DSS} | $I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$, (Figure 12) | 60 | - | - | V |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{GS} = V_{DS}$, $I_D = 250\mu\text{A}$, (Figure 11) | 2 | - | 4 | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = 55\text{V}$, $V_{GS} = 0\text{V}$ | - | - | 1 | μA |
| | | $V_{DS} = 50\text{V}$, $V_{GS} = 0\text{V}$, $T_C = 150^\circ\text{C}$ | - | - | 250 | μA |
| Gate to Source Leakage Current | I_{GSS} | $V_{GS} = \pm 20\text{V}$ | - | - | ± 10 | μA |
| Drain to Source On Resistance | $r_{DS(ON)}$ | $I_D = 2\text{A}$, $V_{GS} = 10\text{V}$, (Figures 9, 10) | - | - | 0.130 | Ω |
| Turn-On Time | t_{ON} | $V_{DD} = 30\text{V}$, $I_D \approx 2\text{A}$, $R_L = 15\Omega$, $V_{GS} = 10\text{V}$, $R_{GS} = 25\Omega$ (Figure 14) | - | - | 50 | ns |
| Turn-On Delay Time | $t_{d(ON)}$ | | - | 10 | - | ns |
| Rise Time | t_r | | - | 25 | - | ns |
| Turn-Off Delay Time | $t_{d(OFF)}$ | | - | 70 | - | ns |
| Fall Time | t_f | | - | 35 | - | ns |
| Turn-Off Time | t_{OFF} | | - | - | - | 155 |
| Total Gate Charge | $Q_g(TOT)$ | $V_{GS} = 0\text{V}$ to 20V | - | 26 | 32 | nC |
| Gate Charge at 10V | $Q_g(10)$ | $V_{GS} = 0\text{V}$ to 10V | | | | |
| Threshold Gate Charge | $Q_g(TH)$ | $V_{GS} = 0\text{V}$ to 2V | | | | |
| Input Capacitance | C_{ISS} | $V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$ (Figure 13) | - | 340 | - | pF |
| Output Capacitance | C_{OSS} | | - | 140 | - | pF |
| Reverse Transfer Capacitance | C_{RSS} | | - | 40 | - | pF |
| Thermal Resistance Junction to Ambient | $R_{\theta JA}$ | Pulse Width = 1s Device Mounted on FR-4 Material | - | - | 62.5 | $^\circ\text{C/W}$ |

Source to Drain Diode Specifications

| PARAMETER | SYMBOL | TEST CONDITIONS | MIN | TYP | MAX | UNITS |
|-------------------------------|----------|---|-----|-----|-----|-------|
| Source to Drain Diode Voltage | V_{SD} | $I_{SD} = 2\text{A}$ | - | - | 1.5 | V |
| Reverse Recovery Time | t_{rr} | $I_{SD} = 2\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$ | - | - | 62 | ns |

RF1K49154

Typical Performance Curves $T_A = 25^\circ\text{C}$, Unless Otherwise Specified

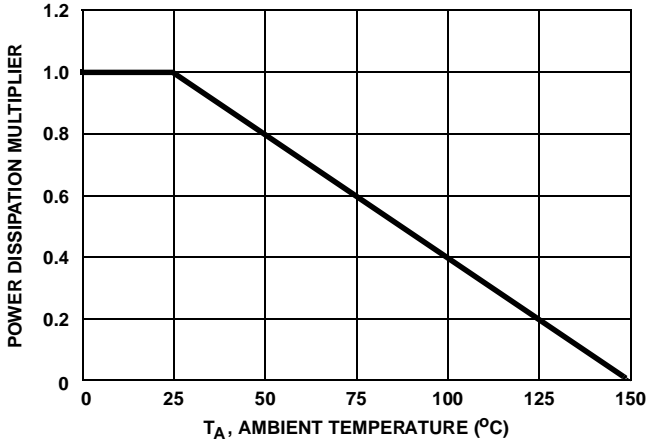


FIGURE 1. NORMALIZED POWER DISSIPATION vs AMBIENT TEMPERATURE

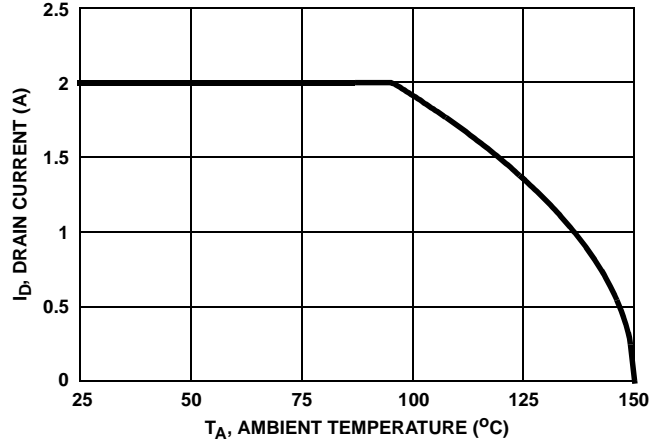


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs AMBIENT TEMPERATURE

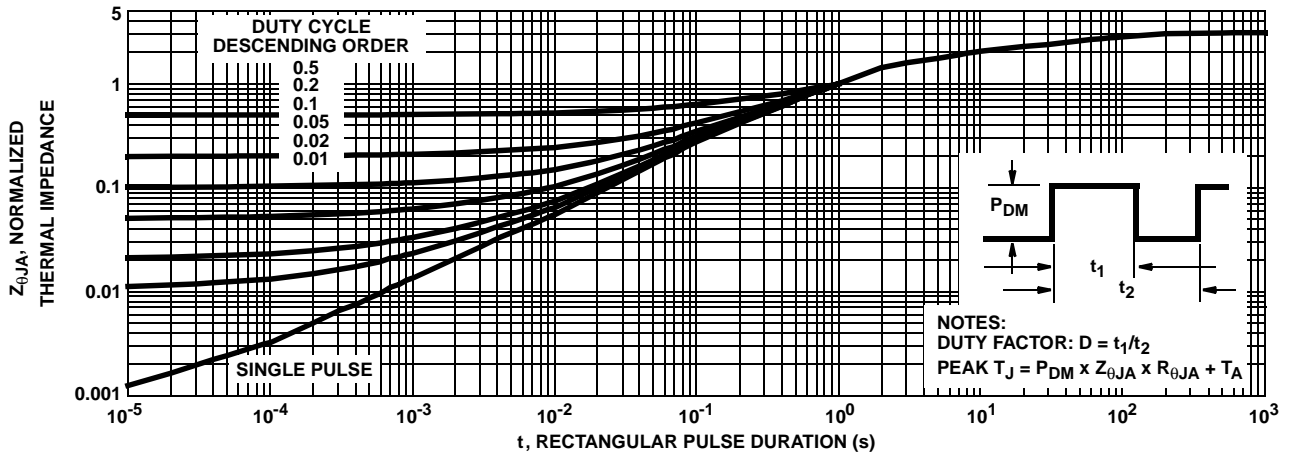


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

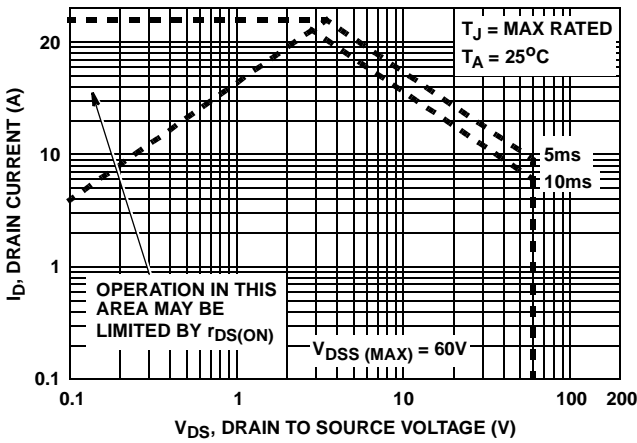


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

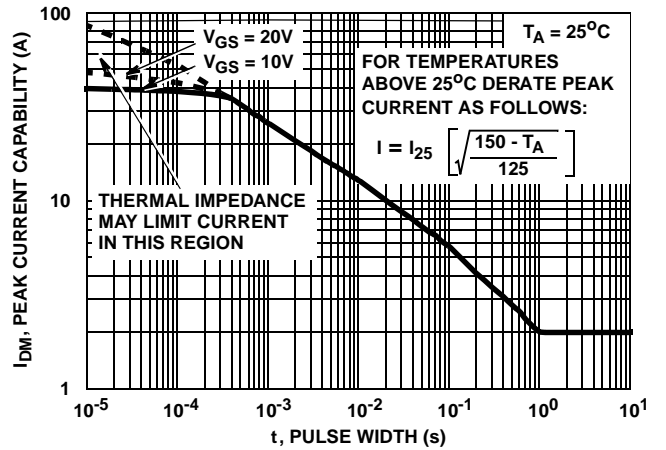
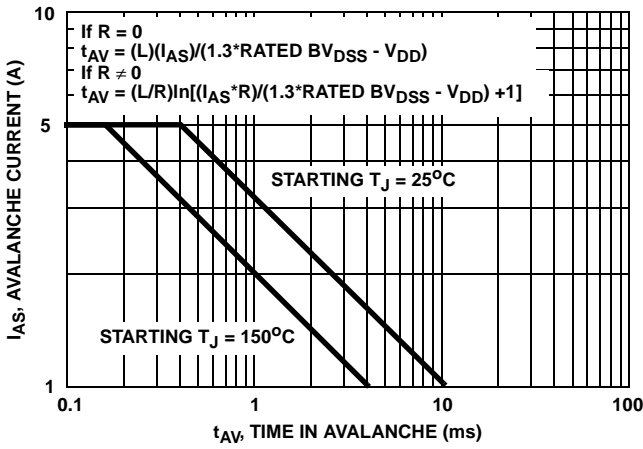


FIGURE 5. PEAK CURRENT CAPABILITY

Typical Performance Curves $T_A = 25^\circ\text{C}$, Unless Otherwise Specified (Continued)



NOTE: Refer to Fairchild Application Notes AN9321 and AN9322.
FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

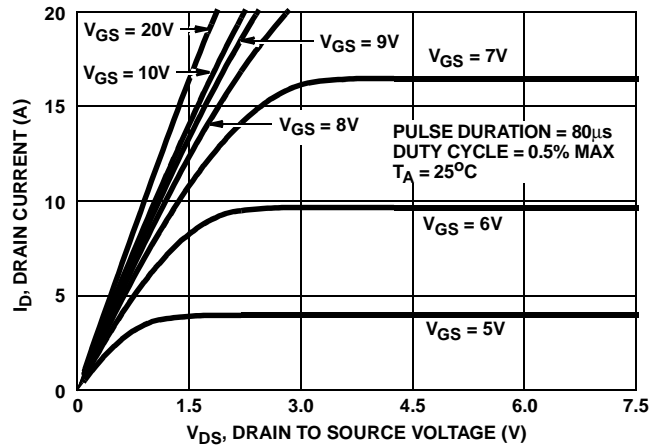


FIGURE 7. SATURATION CHARACTERISTICS

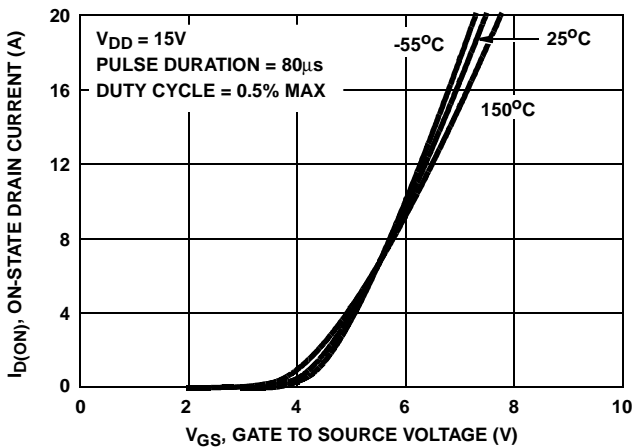


FIGURE 8. TRANSFER CHARACTERISTICS

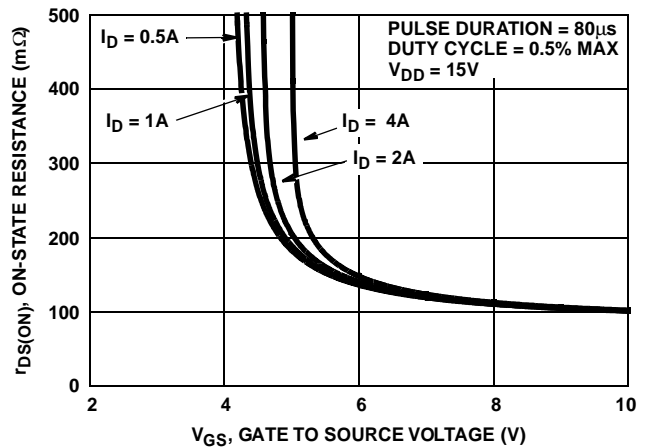


FIGURE 9. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

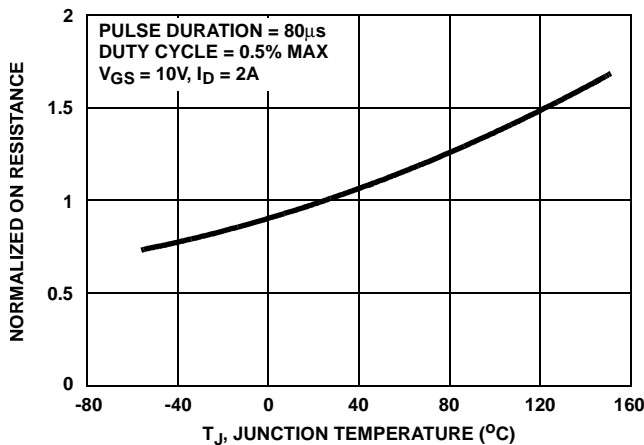


FIGURE 10. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

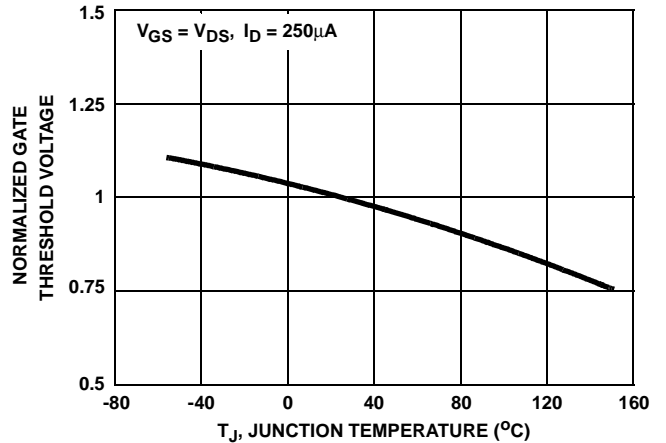


FIGURE 11. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

Typical Performance Curves $T_A = 25^\circ\text{C}$, Unless Otherwise Specified (Continued)

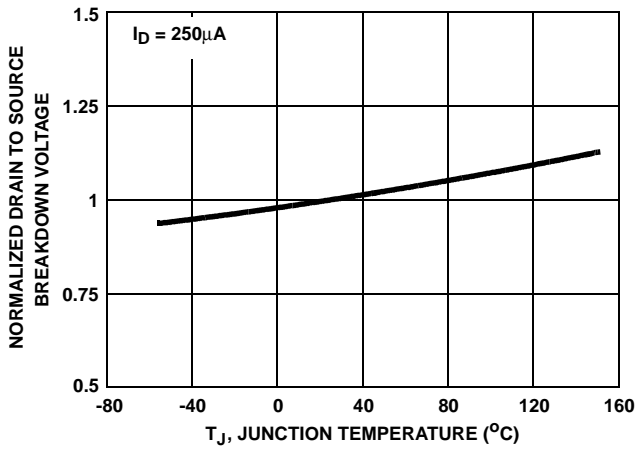


FIGURE 12. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

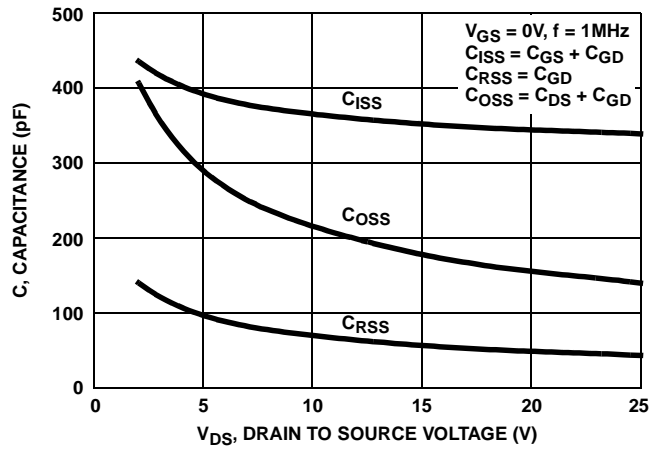
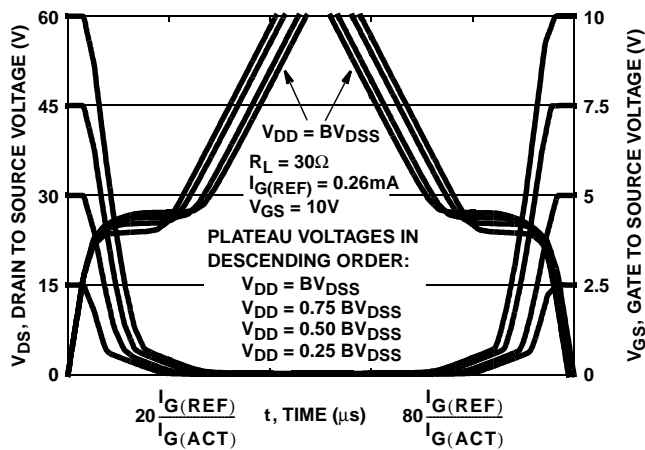


FIGURE 13. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260.

FIGURE 14. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT

Test Circuits and Waveforms

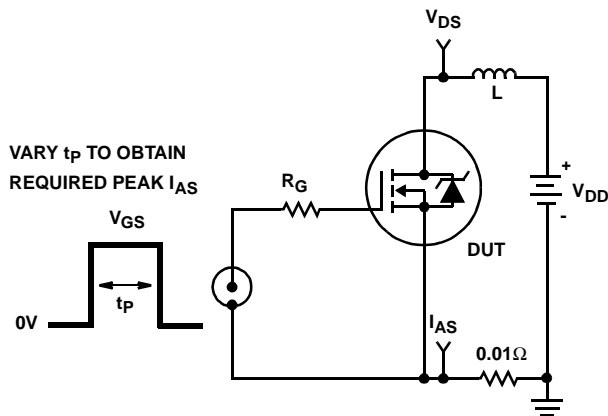


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

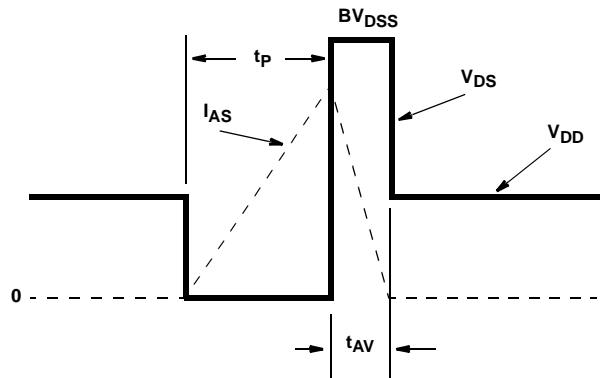


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

Test Circuits and Waveforms (Continued)

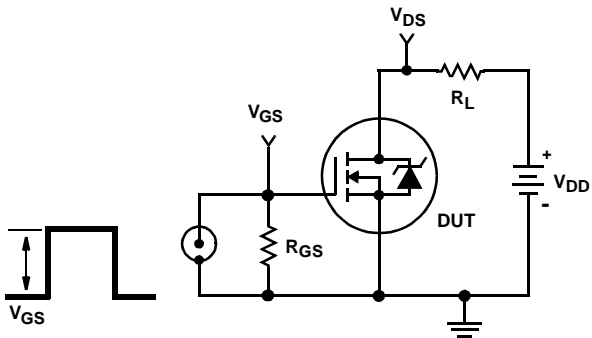


FIGURE 17. SWITCHING TIME TEST CIRCUIT

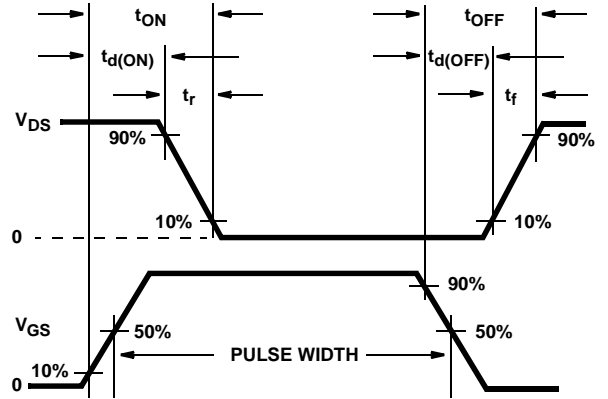


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

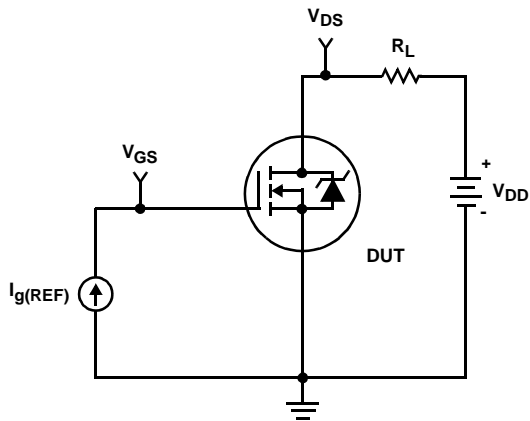


FIGURE 19. GATE CHARGE TEST CIRCUIT

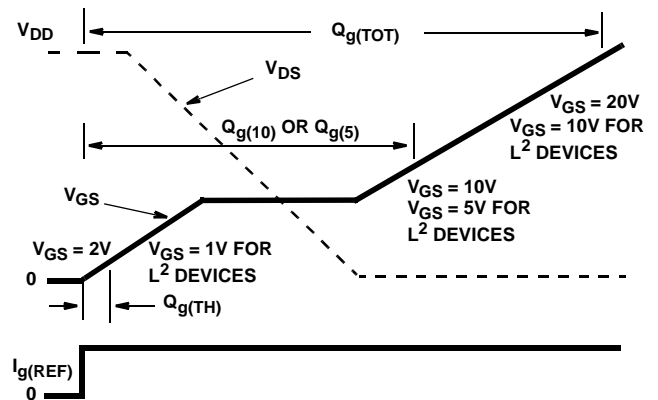


FIGURE 20. GATE CHARGE WAVEFORMS

RF1K49154

PSPICE Electrical Model

SUBCKT RF1K49154 2 1 3 ; rev 2/2/96

CA 12 8 3.5e-10
 CB 15 14 3.7e-10
 CIN 6 8 2.26e-10

DBODY 7 5 DBODYMOD
 DBREAK 5 11 DBREAKMOD
 DPLCAP 10 5 DPLCAPMOD

EBREAK 11 7 17 18 63
 EDS 14 8 5 8 1
 EGS 13 8 6 8 1
 ESG 6 10 6 8 1
 EVTHRES 6 21 19 8 1
 EVTEMP 20 6 18 22 1

IT 8 17 1

LDRAIN 2 5 1e-9
 LGATE 1 9 1.4e-9
 LSOURCE 3 7 3.1e-10
 K1 LGATE LSOURCE 0.131

MMED 16 6 8 8 MMEDMOD
 MSTRO 16 6 8 8 MSTROMOD
 MWEAK 16 21 8 8 MWEAKMOD

RBREAK 17 18 RBREAKMOD 1
 RDRAIN 50 16 RDRAINMOD 7.0e-3
 RGATE 9 20 1.9
 RLDRAIN 2 5 10
 RLGATE 1 9 14
 RLSOURCE 3 7 3
 RSLC1 5 51 RSLCMOD 1e-6
 RSLC2 5 50 1e3
 RSOURCE 8 7 RSOURCEMOD 5.6e-2
 RVTHRES 22 8 RVTHRESMOD 1
 RVTEMP 18 19 RVTEMPMOD 1

S1A 6 12 13 8 S1AMOD
 S1B 13 12 13 8 S1BMOD
 S2A 6 15 14 13 S2AMOD
 S2B 13 15 14 13 S2BMOD

VBAT 22 19 DC 1

ESLC 51 50 VALUE={{(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*50),3))}}

.MODEL DBODYMOD D (IS = 2.6e-13 RS = 2.34e-2 IKF = 5.5 N = 0.995 TRS1 = 2.8e-3 TRS2 = 1.1e-5 CJO = 3.7e-10 TT = 3.5e-8 M = 0.46 + XTI = 5.5)

.MODEL DBREAKMOD D (RS = 0. 5IKF = 0.1 N = 1 TRS1 = 3e- 3TRS2 = -5e-5)

.MODEL DPLCAPMOD D (CJO = 5.6e-1 0IS = 1e-3 0N = 10 M = 0.92)

.MODEL MMEDMOD NMOS (VTO = 3.25 KP = 1.8 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 1.9)

.MODEL MSTROMOD NMOS (VTO = 3.68 KP = 13.5 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u)

.MODEL MWEAKMOD NMOS (VTO = 2.83 KP = 0.03 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 19 RS = 0.1)

.MODEL RBREAKMOD RES (TC1 = 1.08e- 3TC2 = 5e-7)

.MODEL RDRAINMOD RES (TC1 = 1.7e-2 TC2 = 1e-4)

.MODEL RSLCMOD RES (TC1 = 1e-9 TC2 = 1e-4)

.MODEL RSOURCEMOD RES (TC1 = 3.3e-3 TC2 = 1e-9)

.MODEL RVTHRESMOD RES (TC1 = -1.9e-3 TC2 = -4e-6)

.MODEL RVTEMPMOD RES (TC1 = -2.9e- 3TC2 = 2.2e-6)

.MODEL S1AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -7.1 VOFF = -4)

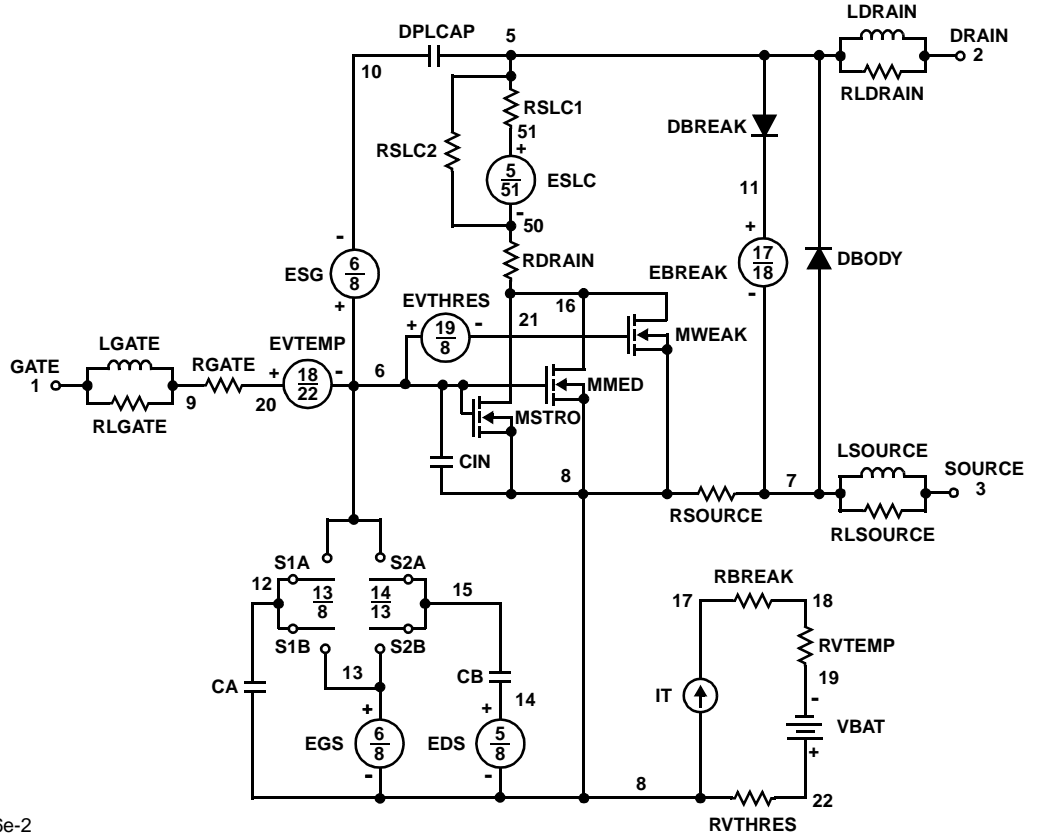
.MODEL S1BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -4 VOFF = -7.1)

.MODEL S2AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = 0.01 VOFF = 1.9)

.MODEL S2AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = 1.9 VOFF = 0.01)

.ENDS

NOTE: For further discussion of the PSPICE model, consult **A New PSPICE Sub-circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991.



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